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Form PTO-1449 (REV. 1/06) INFORMATION DISCLOSURE STATEMENT (Use several sheets if necessary)			US Dept. of Commerce PATENT & TRADEMARK OFFICE	ATTY DOCKET NO. 127438	APPLICATION NO. New U.S. National Stage of 10/572,906 PCT/FR2004/002517
			APPLICANTS Bernard DIENY et al.		
			FILING DATE March 21, 2006		2827

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EXAMINER		DATE CONSIDERED 04/04/2007
Examiner: Initial if citation considered, whether or not citation is in conformance with M.P.E.P. 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.		

Date: March 21, 2006